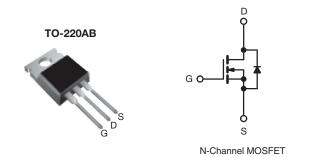


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	800				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 3.0				
Q _g (Max.) (nC)	78				
Q _{gs} (nC)	9.6				
Q _{gd} (nC)	45				
Configuration	Single				



FEATURES

- · Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220AB package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220AB contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION				
Package	TO-220AB			
Lead (Pb)-free	IRFBE30PbF			
Lead (Pb)-nee	SiHFBE30-E3			
SnPb	IRFBE30			
SILL	SiHFBE30			

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	800	.,
Gate-Source Voltage			V_{GS}	± 20	V
Continuous Proin Current	V _{GS} at 10 V	T _C = 25 °C		4.1	
Continuous Drain Current	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	I _D	2.6	Α
Pulsed Drain Current ^a			I _{DM}	16	
Linear Derating Factor				1.0	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	260	mJ
Repetitive Avalanche Current ^a			I _{AR}	4.1	Α
Repetitive Avalanche Energy ^a		E _{AR}	13	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	125	W
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature) for 10 s					
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in
Mounting Torque				1.1	N · m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 29 \,^{\circ}\text{MH}$, $R_q = 25 \,^{\circ}\Omega$, $I_{AS} = 4.1 \,^{\circ}\text{A}$ (see fig. 12).
- c. $I_{SD} \le 4.1 \text{ A}$, $dI/dt \le 100 \text{ A/}\mu\text{s}$, $V_{DD} \le 600$, $T_J \le 150 \,^{\circ}\text{C}$.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0			

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.9	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	\	/ _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = 800 V, V _{GS} = 0 V V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C		-	100 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	-	3.0	Ω
Forward Transconductance	9 _{fs}		100 V, I _D = 2.5 A ^b	2.5	_	-	S
Dynamic	0.0						
Input Capacitance	C _{iss}	1	$V_{GS} = 0 V$,	-	1300	-	
Output Capacitance	C _{oss}	1	$V_{DS} = 25 V,$	-	310	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0	0 MHz, see fig. 5	-	190	-	Ē
Total Gate Charge	Qg			-	-	78	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 4.1 \text{ A}, V_{DS} = 400 \text{ V},$		-	9.6	nC
Gate-Drain Charge	Q _{gd}	1	see fig. 6 and 13 ^b	-	-	45	1
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V, } I_D = 4.1 \text{ A}$ $R_g = 12 \Omega, R_D = 95 \Omega, \text{ see fig. } 10^b$		-	12	-	- ns
Rise Time	t _r			-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") fr	Between lead, 6 mm (0.25") from		4.5	-	
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.1	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	16	A
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 4.1 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 4.1 A, dI/dt = 100 A/μs ^b		1	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	μC
Forward Turn-On Time	t _{on}	Intrinsic tur	n-on time is negligible (turn	rn-on is dominated by L _S and L _D)			

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

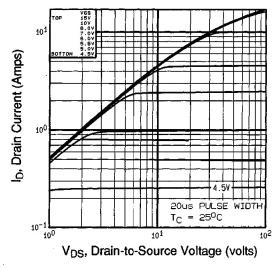


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

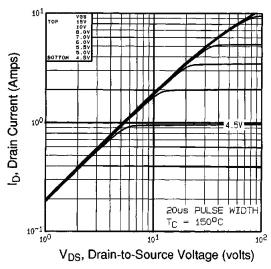
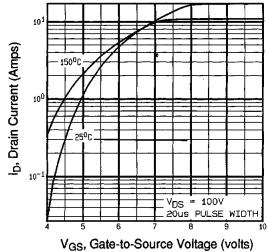


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C



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Fig. 3 - Typical Transfer Characteristics

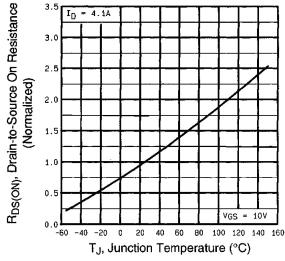


Fig. 4 - Normalized On-Resistance vs. Temperature



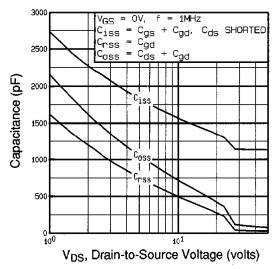


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

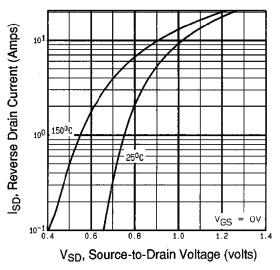


Fig. 7 - Typical Source-Drain Diode Forward Voltage

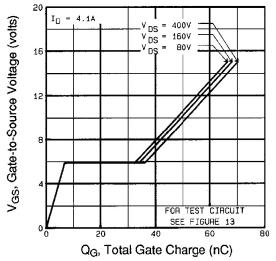


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

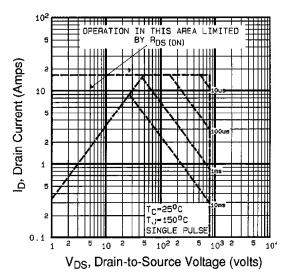


Fig. 8 - Maximum Safe Operating Area





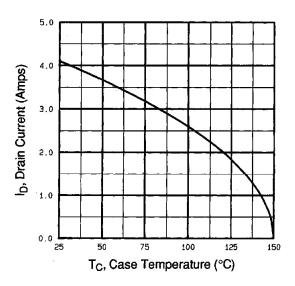


Fig. 9 - Maximum Drain Current vs. Case Temperature

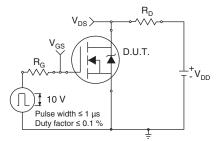


Fig. 10a - Switching Time Test Circuit

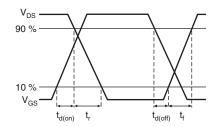
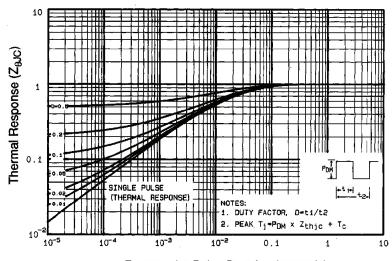


Fig. 10b - Switching Time Waveforms



t₁, Rectangular Pulse Duration (seconds)

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



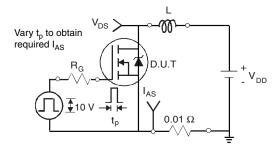


Fig. 12a - Unclamped Inductive Test Circuit

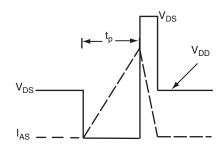


Fig. 12b - Unclamped Inductive Waveforms

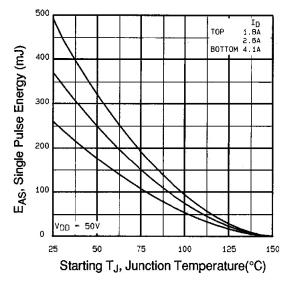


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

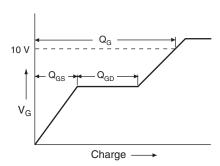


Fig. 13a - Basic Gate Charge Waveform

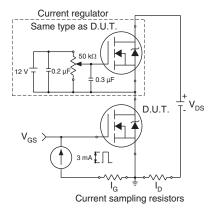
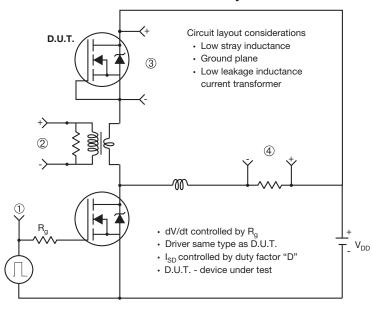


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



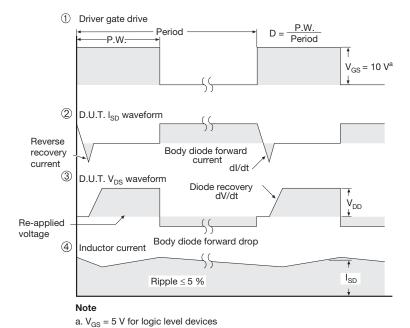


Fig. 14 - For N-Channel

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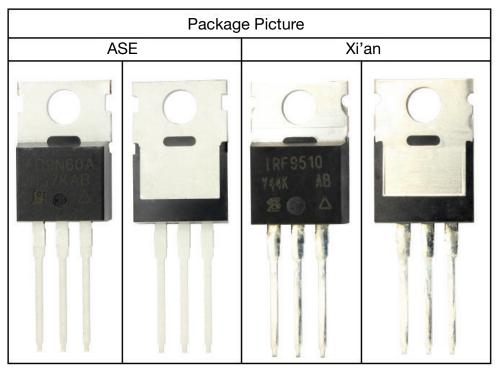
TO-220-1



DIM	MILLIN	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.24	4.65	0.167	0.183		
b	0.69	1.02	0.027	0.040		
b(1)	1.14	1.78	0.045	0.070		
С	0.36	0.61	0.014	0.024		
D	14.33	15.85	0.564	0.624		
E	9.96	10.52	0.392	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.10	6.71	0.240	0.264		
J(1)	2.41	2.92	0.095	0.115		
L	13.36	14.40	0.526	0.567		
L(1)	3.33	4.04	0.131	0.159		
ØР	3.53	3.94	0.139	0.155		
Q	2.54	3.00	0.100	0.118		
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031						

Note

 \bullet $M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



Revison: 14-Dec-15 1 Document Number: 66542



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Revision: 13-Jun-16 1 Document Number: 91000